

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MAWST ET AL.	
		10/772,573	Examiner	Art Unit 2826
Thomas L. Dickey		Page 1 of 1		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Shan et al., "Band Anticrossing in GaInNAs Alloys," Phys. Rev. Lett. Vol. 82, No. 6, pp 1221-1224 (1999)
	V	Press Release, "Striking Effects Of Nitrogen In Semiconductor Alloy Explained," Lawrence Berkeley National Laboratory, June 9, 1999 ( <a href="http://www.sciencedaily.com/releases/1999/06/990609072619.htm">http://www.sciencedaily.com/releases/1999/06/990609072619.htm</a> )
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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